

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/563,437	TAKAYAMA ET AL.	
		Examiner	Art Unit	Page 1 of 1
		Deborah Yee	1793	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,936,169	08-1999	Pinnow et al.	75/246
*	B	US-7,297,177	11-2007	Sandberg et al.	75/246
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2002/070769	09-2002	WIPO	Sandberg et al.	-----
	O	02-138442	05-1990	Japan	Sakai et al.	-----
	P	08-109450	04-1996	Japan	Takeshi et al.	-----
	Q	360050151	03-1985	Japan	Iijima et al.	-----
	R	363262402	10-1988	Japan	Morishita et al.	-----
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.